


<b>Search Notes</b>  	<b>Application/Control No.</b>  10528844	<b>Applicant(s)/Patent Under Reexamination</b>  HOSHINO ET AL.
	<b>Examiner</b>  IQBAL H CHOWDHURY	<b>Art Unit</b>  1652

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
435	125, 122, 6, 69.1, 320.1, 252.3, 254.9, 190	5/6/2008	IC
526	23.2	5/6/2008	IC
STIC:	SEQ ID NO: 1 and 2 against US patent and pending databases	5/6/2008	IC